Preferred Device

Triacs

Silicon Bidirectional Thyristors

Designed for high performance full-wave ac control applications where high noise immunity and high commutating di/dt are required.

Features

- Blocking Voltage to 800 Volts
- On-State Current Rating of 16 Amperes RMS at 80°C
- Uniform Gate Trigger Currents in Three Quadrants
- High Immunity to dv/dt 500 V/µs minimum at 125°C
- Minimizes Snubber Networks for Protection
- Industry Standard TO-220AB Package
- High Commutating di/dt 9.0 A/ms minimum at 125°C
- Pb–Free Packages are Available*

MAXIMUM RATINGS (T_J = 25° C unless otherwise noted)

Rating	Symbol	Value	Unit
Peak Repetitive Off–State Voltage (Note 1) ($T_J = -40$ to 125°C, Sine Wave, 50 to 60 Hz, Gate Open)	V _{DRM,} V _{RRM}		V
MAC16D MAC16M MAC16N		400 600 800	
On-State RMS Current (Full Cycle Sine Wave, 60 Hz, T _C = 80°C)	I _{T(RMS)}	16	A
Peak Non-Repetitive Surge Current (One Full Cycle Sine Wave, 60 Hz, $T_J = 125^{\circ}$ C)	I _{TSM}	150	A
Circuit Fusing Consideration (t = 8.3 ms)	l ² t	93	A ² sec
Peak Gate Power (Pulse Width \leq 1.0 µs, T _C = 80°C)	P _{GM}	20	W
Average Gate Power (t = 8.3 ms, $T_C = 80^{\circ}C$)	P _{G(AV)}	0.5	W
Operating Junction Temperature Range	TJ	-40 to +125	°C
Storage Temperature Range	T _{stg}	-40 to +150	°C

Maximum ratings are those values beyond which device damage can occur. Maximum ratings applied to the device are individual stress limit values (not normal operating conditions) and are not valid simultaneously. If these limits are exceeded, device functional operation is not implied, damage may occur and reliability may be affected.

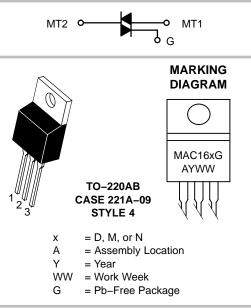
 V_{DRM} and V_{RRM} for all types can be applied on a continuous basis. Blocking voltages shall not be tested with a constant current source such that the voltage ratings of the devices are exceeded.



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	PIN ASSIGNMENT
1	Main Terminal 1
2	Main Terminal 2
3	Gate
4	Main Terminal 2

ORDERING INFORMATION

Device	Package	Shipping
MAC16D	TO-220AB	50 Units / Rail
MAC16DG	TO-220AB (Pb-Free)	50 Units / Rail
MAC16M	TO-220AB	50 Units / Rail
MAC16MG	TO-220AB (Pb-Free)	50 Units / Rail
MAC16N	TO-220AB	50 Units / Rail
MAC16NG	TO-220AB (Pb-Free)	50 Units / Rail

*For additional information on our Pb–Free strategy and soldering details, please download the ON Semiconductor Soldering and Mounting Techniques Reference Manual, SOLDERRM/D.

Preferred devices are recommended choices for future use and best overall value.

THERMAL CHARACTERISTICS

Characteristic	Symbol	Value	Unit
Thermal Resistance, Junction-to-Case Junction-to-Ambient	$R_{ hetaJC}$ $R_{ hetaJA}$	2.0 62.5	°C/W
Maximum Lead Temperature for Soldering Purposes 1/8" from Case for 10 Seconds	TL	260	°C

ELECTRICAL CHARACTERISTICS (T_J = 25°C unless otherwise noted; Electricals apply in both directions)

Characteristic			Min	Тур	Max	Unit
OFF CHARACTERISTICS					1	
Peak Repetitive Blocking Current (V _D = Rated V _{DRM} , V _{RRM} ; Gate Open)	T _J = 25°C T _J = 125°C	I _{DRM} , I _{RRM}			0.01 2.0	mA
ON CHARACTERISTICS				•	•	
Peak On-State Voltage (Note 2) $(I_{TM} = \pm 21 \text{ A Peak})$		V _{TM}	-	1.2	1.6	V
Gate Trigger Current (Continuous dc) ($V_D = 12 V$, $R_L = 100 \Omega$) MT2(+), G(+) MT2(+), G(-) MT2(-), G(-)		I _{GT}	10 10 10	16 18 22	50 50 50	mA
Holding Current ($V_D = 12 V$, Gate Open, Initiating Current = ±150 mA)		I _H	-	20	50	mA
Latching Current (V _D = 24 V, I_G = 50 mA) MT2(+), G(+) MT2(+), G(-) MT2(-), G(-)		ΙL		33 36 33	50 80 50	mA
Gate Trigger Voltage (V_D = 12 V, R_L = 100 Ω) MT2(+), G(+) MT2(+), G(-) MT2(-), G(-)		V _{GT}	0.5 0.5 0.5	0.75 0.72 0.82	1.5 1.5 1.5	V
DYNAMIC CHARACTERISTICS		•				
Rate of Change of Commutating Current, See Figure 10. ($V_D = 400 \text{ V}$, $I_{TM} = 6.0 \text{ A}$, Commutating dv/dt = 24 V/µs, Gate Open, $T_J = 125^{\circ}$ C, f = 250 Hz, No Snubber)	C _L = 10 μF L _L = 40 mH	(di/dt) _c	9.0	-	_	A/ms

dv/dt

500

_

_

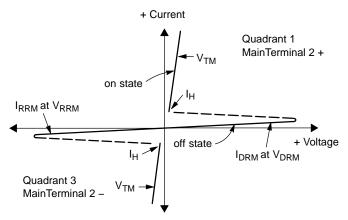
V/μs

(V_D = Rated V_{DRM}, Exponential Waveform, Gate Open, T_J = 125°C)
2. Indicates Pulse Test: Pulse Width ≤ 2.0 ms, Duty Cycle ≤ 2%.

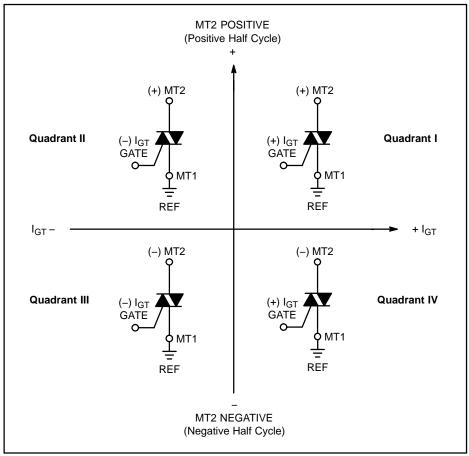
Critical Rate of Rise of Off-State Voltage

Voltage Current Characteristic of Triacs (Bidirectional Device)

Symbol	Parameter
V _{DRM}	Peak Repetitive Forward Off State Voltage
I _{DRM}	Peak Forward Blocking Current
V _{RRM}	Peak Repetitive Reverse Off State Voltage
I _{RRM}	Peak Reverse Blocking Current
V _{TM}	Maximum On State Voltage
I _Н	Holding Current

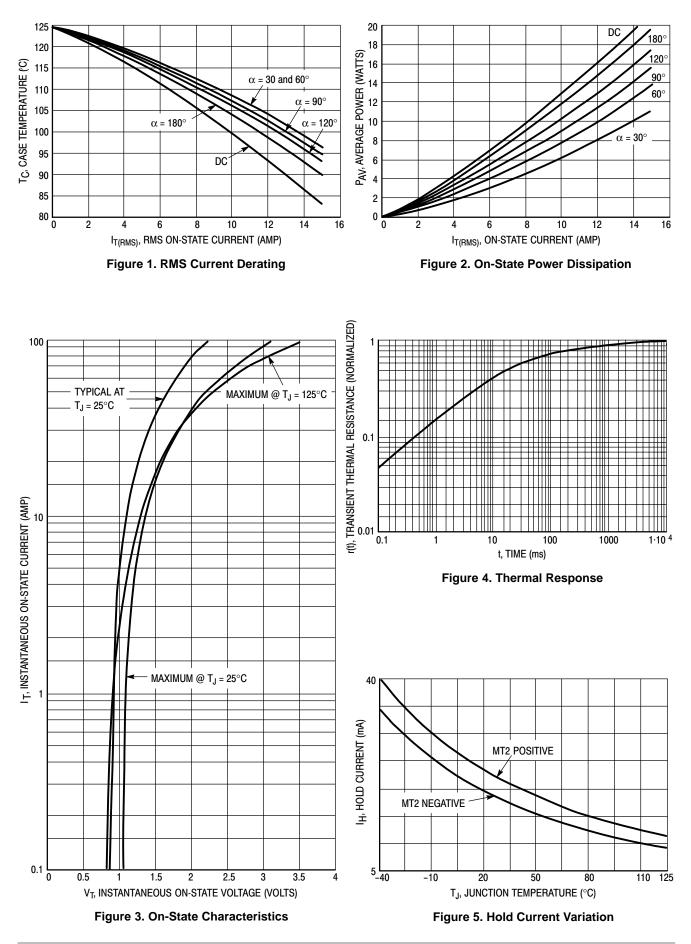


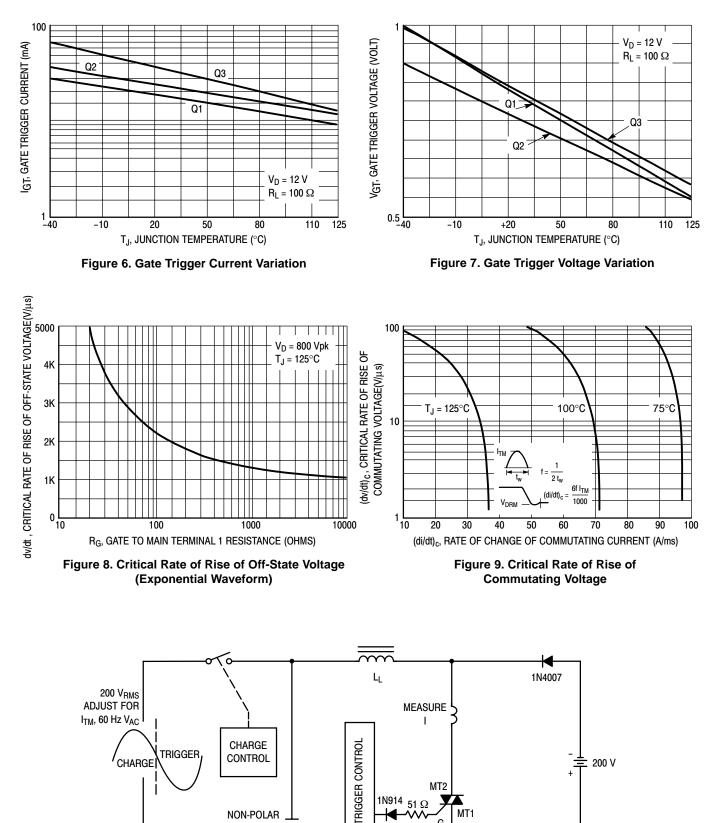
Quadrant Definitions for a Triac

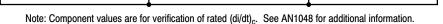


All polarities are referenced to MT1.

With in-phase signals (using standard AC lines) quadrants I and III are used.







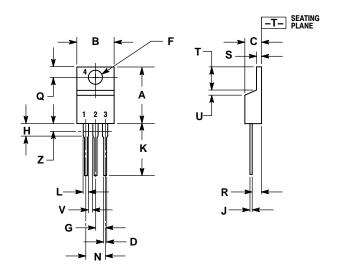
 C_{L}

G

Figure 10. Simplified Test Circuit to Measure the Critical Rate of Rise of Commutating Current (di/dt)_c

PACKAGE DIMENSIONS

TO-220AB CASE 221A-09 ISSUE AA



NOTES:

 DIMENSIONING AND TOLERANCING PER ANSI Y14.5M, 1982.
 CONTROLLING DIMENSION: INCH.

 CONTROLLING DIMENSION: INCH.
 DIMENSION Z DEFINES A ZONE WHERE ALL BODY AND LEAD IRREGULARITIES ARE NUMERON AND LEAD IRREGULARITIES ARE

	INCHES		MILLIN	IETERS
DIM	MIN	MAX	MIN	MAX
Α	0.570	0.620	14.48	15.75
В	0.380	0.405	9.66	10.28
С	0.160	0.190	4.07	4.82
D	0.025	0.035	0.64	0.88
F	0.142	0.147	3.61	3.73
G	0.095	0.105	2.42	2.66
Н	0.110	0.155	2.80	3.93
J	0.018	0.025	0.46	0.64
Κ	0.500	0.562	12.70	14.27
L	0.045	0.060	1.15	1.52
Ν	0.190	0.210	4.83	5.33
Q	0.100	0.120	2.54	3.04
R	0.080	0.110	2.04	2.79
S	0.045	0.055	1.15	1.39
Т	0.235	0.255	5.97	6.47
U	0.000	0.050	0.00	1.27
۷	0.045		1.15	
Z		0.080		2.04

STYLE 4:

PIN 1. MAIN TERMINAL 1 2. MAIN TERMINAL 2

3. GATE 4. MAIN TERMINAL 2

MAIN TERMINAL

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